CD4071BM/CD4071BC Quad 2-Input OR Buffered B Series Gate CD4081BM/CD4081BC Quad 2-Input AND Buffered B Series Gate

General Description

These quad gates are monolithic complementary MOS (CMOS) integrated circuits constructed with N- and P-channel enhancement mode transistors. They have equal source and sink current capabilities and conform to standard B series output drive. The devices also have buffered outputs which improve transfer characteristics by providing very high gain.

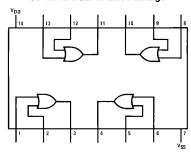
All inputs protected against static discharge with diodes to $V_{\mbox{\footnotesize{DD}}}$ and $V_{\mbox{\footnotesize{SS}}}.$

Features

- Low power TTL Fan out of 2 driving 74L compatibility or 1 driving 74LS
- 5V-10V-15V parametric ratings
- Symmetrical output characteristics
- Maximum input leakage 1 µA at 15V over full temperature range

Connection Diagrams

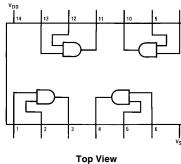
CD4071B Dual-In-Line Package



Top View

TL/F/5977-3

CD4081B Dual-In-Line Package



TL/F/5977-6

Order Number CD4071B or CD4081B

Absolute Maximum Ratings (Notes 1 & 2)

If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/Distributors for availability and specifications.

Voltage at Any Pin -0.5V to $V_{\rm DD} + 0.5V$

Power Dissipation (PD)

Dual-In-Line 700 mW Small Outline 500 mW V_{DD} Range $-0.5\,V_{DC}$ to $\,\pm\,18\,V_{DC}$

Storage Temperature (T_S)

-65°C to +150°C

Lead Temperature (T_L) (Soldering, 10 seconds)

260°C

Operating Conditions

Operating Range (V_{DD})

Operating Temperature Range (T_A)

CD4071BM, CD4081BM CD4071BC, CD4081BC

3 V_{DC} to 15 V_{DC}

-55°C to +125°C -40°C to +85°C

DC Electrical Characteristics CD4071BM/CD4081BM (Note 2)

Symbol	Parameter	Conditions	-5	5°C	,C		+ 25°C		+ 125°C	
Symbol		Conditions	Min	Max	Min	Тур	Max	Min	Max	- Units
I _{DD}	Quiescent Device Current	$V_{DD} = 5V$ $V_{DD} = 10V$ $V_{DD} = 15V$		0.25 0.50 1.0		0.004 0.005 0.006	0.25 0.50 1.0		7.5 15 30	μΑ μΑ μΑ
V _{OL}	Low Level Output Voltage	$ \left \begin{array}{l} V_{DD} = 5V \\ V_{DD} = 10V \\ V_{DD} = 15V \end{array} \right\} \left I_{O} \right < 1 \; \mu A $		0.05 0.05 0.05		0 0 0	0.05 0.05 0.05		0.05 0.05 0.05	V V V
V _{OH}	High Level Output Voltage	$ \begin{vmatrix} V_{DD} = 5V \\ V_{DD} = 10V \\ V_{DD} = 15V \end{vmatrix} I_{O} < 1 \ \mu A $	4.95 9.95 14.95		4.95 9.95 14.95	5 10 15		4.95 9.95 14.95		V V
V _{IL}	Low Level Input Voltage	$V_{DD} = 5V, V_{O} = 0.5V$ $V_{DD} = 10V, V_{O} = 1.0V$ $V_{DD} = 15V, V_{O} = 1.5V$		1.5 3.0 4.0		2 4 6	1.5 3.0 4.0		1.5 3.0 4.0	V V
V _{IH}	High Level Input Voltage	$V_{DD} = 5V, V_{O} = 4.5V$ $V_{DD} = 10V, V_{O} = 9.0V$ $V_{DD} = 15V, V_{O} = 13.5V$	3.5 7.0 11.0		3.5 7.0 11.0	3 6 9		3.5 7.0 11.0		V V
loL	Low Level Output Current (Note 3)	$V_{DD} = 5V, V_{O} = 0.4V$ $V_{DD} = 10V, V_{O} = 0.5V$ $V_{DD} = 15V, V_{O} = 1.5V$	0.64 1.6 4.2		0.51 1.3 3.4	0.88 2.25 8.8		0.36 0.9 2.4		mA mA mA
Гон	High Level Output Current (Note 3)	$V_{DD} = 5V, V_{O} = 4.6V$ $V_{DD} = 10V, V_{O} = 9.5V$ $V_{DD} = 15V, V_{O} = 13.5V$	-0.64 -1.6 -4.2		-0.51 -1.3 -3.4	-0.88 -2.25 -8.8		-0.36 -0.9 -2.4		mA mA mA
I _{IN}	Input Current	$V_{DD} = 15V, V_{IN} = 0V$ $V_{DD} = 15V, V_{IN} = 15V$		-0.10 0.10		-10 ⁻⁵	-0.10 0.10		-1.0 1.0	μA μA

Note 1: "Absolute Maximum Ratings" are those values beyond which the safety of the device cannot be guaranteed. Except for "Operating Temperature Range" they are not meant to imply that the devices should be operated at these limits. The table of "Electrical Characteristics" provides conditions for actual device

Note 2: All voltages measured with respect to V_{SS} unless otherwise specified.

Note 3: I_{OH} and I_{OL} are tested one output at a time.

DC Electrical Characteristics CD4071BC/CD4081BC (Note 2)

Symbol	Parameter	Conditions	-4	0°C		+ 25°C		+ 85	5°C	Units
Symbol		Conditions	Min	Max	Min	Тур	Max	Min	Max	Oilles
I _{DD}	Quiescent Device Current	$V_{DD} = 5V$ $V_{DD} = 10V$ $V_{DD} = 15V$		1 2 4		0.004 0.005 0.006	1 2 4		7.5 15 30	μΑ μΑ μΑ
V _{OL}	Low Level Output Voltage	$V_{DD} = 5V$ $V_{DD} = 10V$ $V_{DD} = 15V$ $ I_{O} < 1 \mu A$		0.05 0.05 0.05		0 0 0	0.05 0.05 0.05		0.05 0.05 0.05	\ \ \ \ \ \
V _{OH}	High Level Output Voltage	$ \begin{vmatrix} V_{DD} = 5V \\ V_{DD} = 10V \\ V_{DD} = 15V \end{vmatrix} I_O < 1 \mu A $	4.95 9.95 14.95		4.95 9.95 14.95	5 10 15		4.95 9.95 14.95		V V
V _{IL}	Low Level Input Voltage	$V_{DD} = 5V, V_{O} = 0.5V$ $V_{DD} = 10V, V_{O} = 1.0V$ $V_{DD} = 15V, V_{O} = 1.5V$		1.5 3.0 4.0		2 4 6	1.5 3.0 4.0		1.5 3.0 4.0	V V
V _{IH}	High Level Input Voltage	$V_{DD} = 5V, V_{O} = 4.5V$ $V_{DD} = 10V, V_{O} = 9.0V$ $V_{DD} = 15V, V_{O} = 13.5V$	3.5 7.0 11.0		3.5 7.0 11.0	3 6 9		3.5 7.0 11.0		V V
l _{OL}	Low Level Output Current (Note 3)	$V_{DD} = 5V, V_{O} = 0.4V$ $V_{DD} = 10V, V_{O} = 0.5V$ $V_{DD} = 15V, V_{O} = 1.5V$	0.52 1.3 3.6		0.44 1.1 3.0	0.88 2.25 8.8		0.36 0.9 2.4		mA mA mA
l _{OH}	High Level Output Current (Note 3)	$V_{DD} = 5V, V_{O} = 4.6V$ $V_{DD} = 10V, V_{O} = 9.5V$ $V_{DD} = 15V, V_{O} = 13.5V$	-0.52 -1.3 -3.6		-0.44 -1.1 -3.0	-0.88 -2.25 -8.8		-0.36 -0.9 -2.4		mA mA mA
I _{IN}	Input Current	$V_{DD} = 15V, V_{IN} = 0V$ $V_{DD} = 15V, V_{IN} = 15V$		-0.30 0.30		-10 ⁻⁵	-0.30 0.30		-1.0 1.0	μA μA

AC Electrical Characteristics* $_{CD4071BC/CD4071BM}$ $T_A=25^{\circ}C,$ Input $t_{r};$ $t_f=20$ ns, $C_L=50$ pF, $R_L=200$ k $\Omega,$ Typical temperature coefficient is $0.3\%/^{\circ}C$

Symbol	Parameter	Conditions	Тур	Max	Units
t _{PHL}	Propagation Delay Time,	$V_{DD} = 5V$	100	250	ns
	High-to-Low Level	$V_{DD} = 10V$	40	100	ns
		$V_{DD} = 15V$	30	70	ns
t _{PLH}	Propagation Delay Time,	$V_{DD} = 5V$	90	250	ns
	Low-to-High Level	$V_{DD} = 10V$	40	100	ns
	-	$V_{DD} = 15V$	30	70	ns
t _{THL} , t _{TLH}	Transition Time	$V_{DD} = 5V$	90	200	ns
		$V_{DD} = 10V$	50	100	ns
		$V_{DD} = 15V$	40	80	ns
C _{IN}	Average Input Capacitance	Any Input	5	7.5	pF
C _{PD}	Power Dissipation Capacity	Any Gate	18		pF

 $^{^*\}mbox{AC}$ Parameters are guaranteed by DC correlated testing.

Note 1: "Absolute Maximum Ratings" are those values beyond which the safety of the device cannot be guaranteed. Except for "Operating Temperature Range" they are not meant to imply that the devices should be operated at these limits. The table of "Electrical Characteristics" provides conditions for actual device

Note 2: All voltages measured with respect to $V_{\mbox{\scriptsize SS}}$ unless otherwise specified.

Note 3: I_{OH} and I_{OL} are tested one output at a time.

AC Electrical Characteristics* $_{CD4081BC/CD4081BM}$ $_{T_A}=$ 25°C, Input $t_f;\,t_f=$ 20 ns, $C_L=$ 50 pF, $R_L=$ 200 $k\Omega,$ Typical temperature coefficient is 0.3%/°C

Symbol	Parameter	Conditions	Тур	Max	Units
t _{PHL}	Propagation Delay Time,	$V_{DD} = 5V$	100	250	ns
	High-to-Low Level	$V_{DD} = 10V$	40	100	ns
		$V_{DD} = 15V$	30	70	ns
t _{PLH}	Propagation Delay Time,	$V_{DD} = 5V$	120	250	ns
	Low-to-High Level	$V_{DD} = 10V$	50	100	ns
	·	$V_{DD} = 15V$	35	70	ns
t _{THL} , t _{TLH}	Transition Time	$V_{DD} = 5V$	90	200	ns
		$V_{DD} = 10V$	50	100	ns
		$V_{DD} = 15V$	40	80	ns
C _{IN}	Average Input Capacitance	Any Input	5	7.5	pF
C_{PD}	Power Dissipation Capacity	Any Gate	18		pF

^{*}AC Parameters are guaranteed by DC correlated testing.

Typical Performance Characteristics

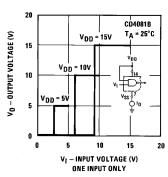


FIGURE 1. Typical Transfer Characteristics

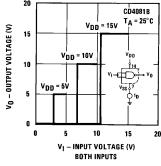


FIGURE 2. Typical Transfer Characteristics

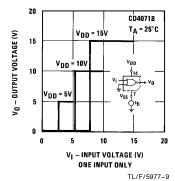


FIGURE 3. Typical Transfer Characteristics

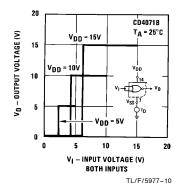
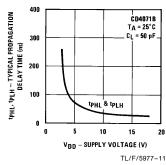
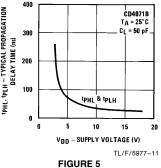


FIGURE 4. Typical Transfer



Characteristics



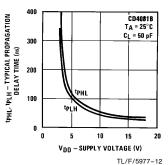
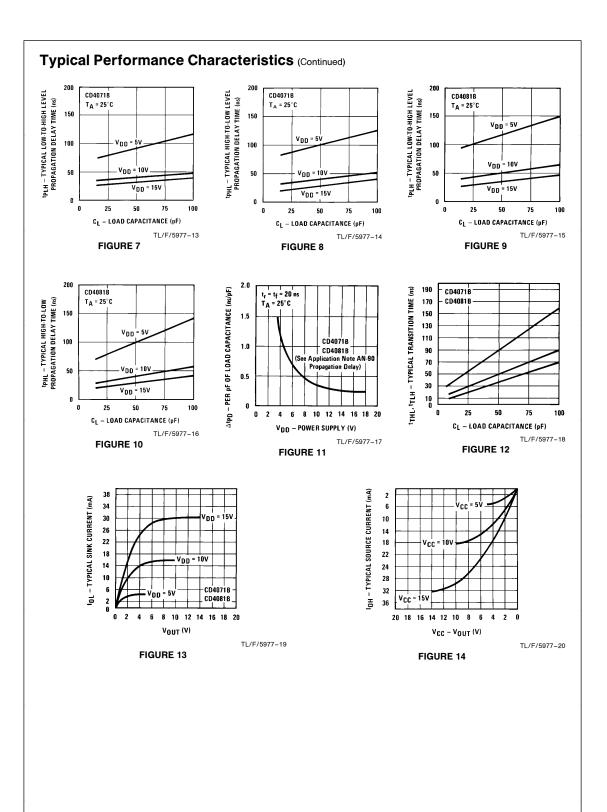
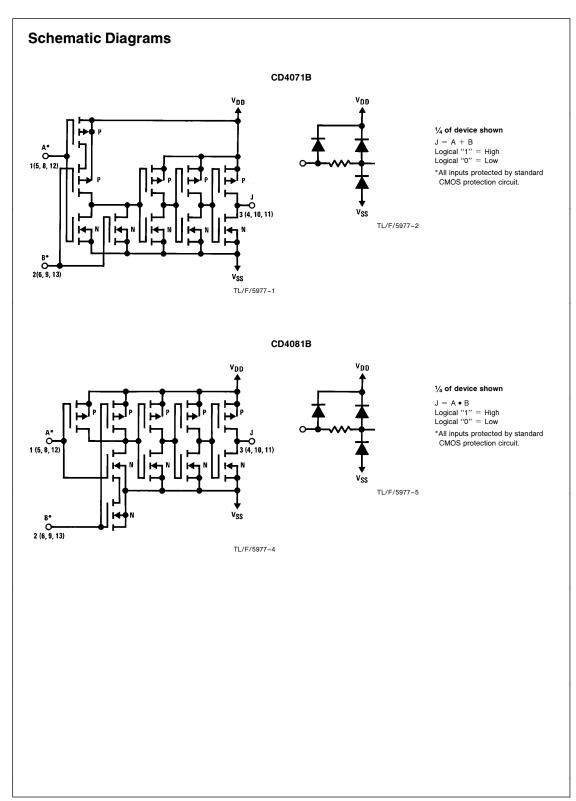
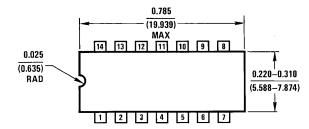


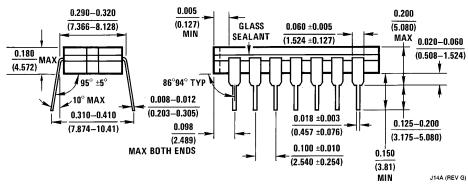
FIGURE 6





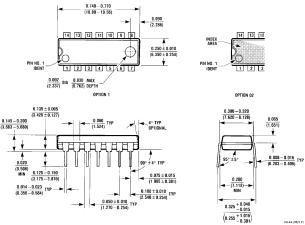






Ceramic Dual-In-Line Package (J)
Order Number CD4071BMJ, CD4071BCJ
CD4081BMJ or CD4081BCJ
NS Package Number J14A

Physical Dimensions inches (millimeters) (Continued)



Molded Dual-In-Line Package (N) Order Number CD4071BMN, CD4071BCN CD4081BMN or CD4081BCN NS Package Number N14A

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